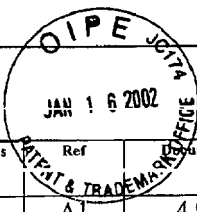


INFORMATION DISCLOSURE 1449		Docket No.: MCA-400 PC/US		Application No.: 09/889,901	
		Applicant: Yen, et al.			
		Filing Date: July 24, 2001		Group Art Unit: 1723	



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* Examiner's Initials	Ref	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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	*B2	EP 0 175 432	03/86	EPO				
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Examiner:

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Date Considered:

8/22/03

Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant

* Indicates a cite that has been previously forwarded to the USPTO and is not enclosed.